

TRENCHSTOP™ IGBT4 Low Power Chip

Features:

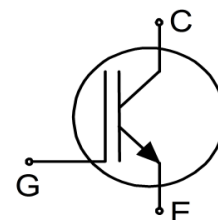
- 1200V trench & field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

Recommended for:

- Low / medium power modules

Applications:

- Low / medium power drives



Chip Type	V_{CE}	I_{Cn}^1	Die Size	Package
IGC36T120T8L	1200V	35A	6.36mm x 5.67mm	Sawn on foil

Mechanical Parameters

Die size		6.36 x 5.67	mm ²
Emitter pad size		See chip drawing	
Gate pad size		0.826 x 1.31	
Area total		36.06	
Thickness		115	μm
Wafer size		200	mm
Maximum possible chips per wafer		743	
Passivation frontside		Photoimide	
Pad metal		3200nm AlSiCu	
Backside metal		Ni Ag – system To achieve a reliable solder connection it is strongly recommended not to consume the Ni layer completely during production process	
Die bond		Electrically conductive epoxy glue and soft solder	
Wire bond		Al, ≤500μm	
Reject ink dot size		Ø 0.65mm; max. 1.2mm	
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C, <6 months	
	for open MBB bags	Acc. to IEC62258-3: atmosphere >99% Nitrogen or inert gas, humidity <25%RH, temperature 17°C – 25°C, <6 months	

¹ Nominal collector current at $T_C=100^\circ\text{C}$ for chip packaged in power modules, see application example cited on page 5.

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage, $T_{vj}=25^{\circ}\text{C}$	V_{CE}	1200	V
DC collector current, limited by $T_{vj\max}^2$	I_C	-	A
Pulsed collector current, t_p limited by $T_{vj\max}^3$	$I_{C,puls}$	105	A
Gate-emitter voltage	V_{GE}	± 20	V
Operating junction temperature	T_{vj}	-40 ... +175	$^{\circ}\text{C}$
Short circuit data ^{3/4} $V_{GE}=15\text{V}$, $V_{CC}=800\text{V}$, $T_{vj}=150^{\circ}\text{C}$	t_{sc}	10	μs

Static Characteristics (tested on wafer), $T_{vj}=25^{\circ}\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0\text{V}$, $I_C=1.2\text{mA}$	1200	-	-	V
Collector-emitter saturation voltage	V_{CEsat}	$V_{GE}=15\text{V}$, $I_C=35\text{A}$	1.58	1.85	2.07	
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=1.2\text{mA}$, $V_{GE}=V_{CE}$	5.3	5.8	6.3	
Zero gate voltage collector current	I_{CES}	$V_{CE}=1200\text{V}$, $V_{GE}=0\text{V}$	-	-	5	μA
Gate-emitter leakage current	I_{GES}	$V_{CE}=0\text{V}$, $V_{GE}=20\text{V}$	-	-	120	nA
Integrated gate resistor	r_G		none			Ω

Electrical Characteristics ³

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter saturation voltage	V_{CEsat}	$V_{GE}=15\text{V}$, $I_C=35\text{A}$, $T_{vj}=150^{\circ}\text{C}$	-	2.25	-	V
Input capacitance	C_{ies}	$V_{CE}=25\text{V}$, $V_{GE}=0\text{V}$, $f=1\text{MHz}$, $T_{vj}=25^{\circ}\text{C}$	-	2000	-	pF
Reverse transfer capacitance	C_{res}		-	70	-	

² Depending on thermal properties of assembly.

³ Not subject to production test - verified by design/characterization.

⁴ Allowed number of short circuits: <1000; time between short circuits: >1s.